EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	433	382/302,304.ccls.	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:47
L2	894	700/4,5.ccls.	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 10:31
L3	52170	parallel near proces$6	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 10:31
L4	1311	1 2	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 10:31
L5	276	3 and 4	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 10:32
L6	1	(parallel and proces$6 and data and stream and nod$2 and (sub adj block) and mismatch and identification and max).clm.	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 10:41
L7	1	(parallel and proces$6 and data and stream and nod$2 and (sub adj block) and mismatch and identification and max).clm.	US-PGPUB	OR	ON	2006/10/12 10:33
L8	120	(compar$3 near block) same (divid$3 near image)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 10:42

EAST Search History

L9	6256	wafer near inspect$3	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 10:43
L10	0	8 same 9	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 10:42
L11	0	8 and 9	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 10:42
L12	18093	(wafer semiconductor) near (defect inspect$3)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 10:44
L13	0	8 and 12	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 10:44

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L7	1	(parallel and proces$6 and data and stream and nod$2 and (sub adj block) and mismatch and identification and max).clm.	US-PGPUB	OR	ON	2006/10/12 10:33

INTERFERENCE TEXT SEARCH